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Titolo	Groupoid Metrization Theory : With Applications to Analysis on Quasi-Metric Spaces and Functional Analysis / / by Dorina Mitrea, Irina Mitrea, Marius Mitrea, Sylvie Monniaux
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Descrizione fisica	1 online resource (485 p.)
Collana	Applied and Numerical Harmonic Analysis, , 2296-5017
Disciplina	514/.325
Soggetti	Harmonic analysis Functional analysis Topology Mathematical analysis Measure theory Algebraic geometry Abstract Harmonic Analysis Functional Analysis Analysis Measure and Integration Algebraic Geometry
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
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Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and indexes.
Nota di contenuto	Introduction -- Semigroupoids and Groupoids -- Quantitative Metrization Theory -- Applications to Analysis on Quasi-Metric Spaces -- Non-Locally Convex Functional Analysis -- Functional Analysis on Quasi-Pseudonormed Groups -- References -- Symbol Index -- Subject Index -- Author Index.
Sommario/riassunto	The topics in this research monograph are at the interface of several areas of mathematics such as harmonic analysis, functional analysis, analysis on spaces of homogeneous type, topology, and quasi-metric geometry. The presentation is self-contained with complete, detailed proofs, and a large number of examples and counterexamples are provided. Unique features of Metrization Theory for Groupoids: With

Applications to Analysis on Quasi-Metric Spaces and Functional Analysis include: * treatment of metrization from a wide, interdisciplinary perspective, with accompanying applications ranging across diverse fields; * coverage of topics applicable to a variety of scientific areas within pure mathematics; * useful techniques and extensive reference material; * includes sharp results in the field of metrization. Professional mathematicians with a wide spectrum of mathematical interests will find this book to be a useful resource and complete self-study guide. At the same time, the monograph is accessible and will be of use to advanced graduate students and to scientifically trained readers with an interest in the interplay among topology and metric properties and/or functional analysis and metric properties.
